Special Issue

Advances in Small Infrared Target Detection Using Deep Learning

Message from the Guest Editor

Remote infrared small target detection is a well-known problem in surveillance areas. Although small infrared targets can be detected successfully in homogeneous sky background, they are still very challenging to detect in cluttered complex backgrounds due to many false alarms. This Special Issue will publish recent advances in small infrared target detection using deep learning methods. The scope is as follows.

- Deep learning-based super-resolution of infrared images;
- Deep learning-based signal-to-noise enhancement;
- Deep learning-based background clutter suppression;
- Deep learning-based panoptic segmentation;
- Deep learning-based small infrared target detection in complex environment;
- Deep learning-based moving infrared target detection.

Keywords

- infrared
- small target
- detection
- deep learning
- clutter

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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